TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type (MACH II π -MOS V)

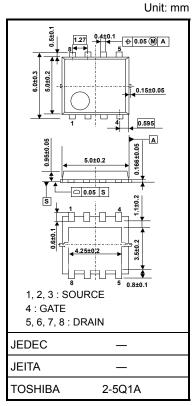
TPCA8008-H

High Speed Switching Applications Switching Regulator Applications DC/DC Converter Applications

- · Small footprint due to a small and thin package
- High-speed switching
- Small gate charge: QSW = 3.7 nC (typ.)
- Low drain-source ON-resistance: $RDS(ON) = 0.47\Omega$ (typ.)
- High forward transfer admittance: $|Y_{fs}| = 3.3S$ (typ.)
- Low leakage current: $IDSS = 100 \mu A (max) (VDS = 250 V)$
- Enhancement mode: $V_{th} = 2.0 \text{ to } 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA)}$

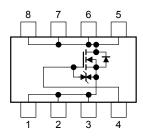
Absolute Maximum Ratings (Ta = 25°C)

Characte	eristic	Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	250	V	
Drain-gate voltage (R	$k_{GS} = 20 \text{ k}\Omega$)	V_{DGR}	250	V	
Gate-source voltage		V_{GSS}	±20	V	
Drain current	DC (Note 1)	I _D	4	Α	
Diam current	Pulsed (Note 1)	I _{DP}	8		
Drain power dissipation	on (Tc=25°C)	P_{D}	45	W	
Drain power dissipation	on (t = 10 s) (Note 2a)	P _D	2.8	W	
Drain power dissipation (t = 10 s) (Note 2b)		P _D	1.6	W	
Single-pulse avalance	ne energy (Note 3)	E _{AS}	11	mJ	
Avalanche current		I _{AR}	4	Α	
Repetitive avalanche energy (Tc=25°C) (Note 4)		E _{AR}	4.5	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55 to 150	°C	



Weight: 0.069 g (typ.)

Circuit Configuration



Note: For Notes 1 to 4, refer to the next page.

Using continuously under heavy loads (e.g. the application of high

temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

This transistor is an electrostatic-sensitive device. Handle with care.

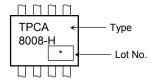
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Thermal Characteristics

Characteristic	Symbol	Max	Unit
Thermal resistance, channel to case (Tc=25°C)	R _{th (ch-c)}	2.78	°C/W
Thermal resistance, channel to ambient (t = 10 s) (Note 2a)	R _{th (ch-a)}	44.6	°C/W
Thermal resistance, channel to ambient (t = 10 s) (Note 2b)	R _{th (ch-a)}	78.1	°C/W

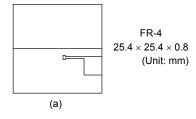
Marking (Note 5)

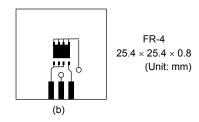


Note 1: The channel temperature should not exceed 150°C during use.

Note 2: (a) Device mounted on a glass-epoxy board (a)

(b) Device mounted on a glass-epoxy board (b)

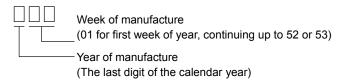




Note 3: $V_{DD} = 50 \text{ V}$, $T_{ch} = 25^{\circ}\text{C}$ (initial), L = 1mH, $R_G = 25 \ \Omega$, $I_{AR} = 4 \ A$

Note 4: Repetitive rating: pulse width limited by max channel temperature

Note 5: * Weekly code: (Three digits)



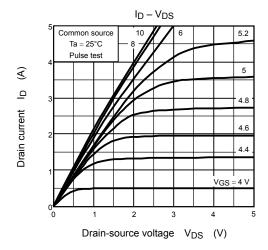


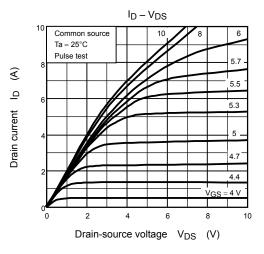
Electrical Characteristics (Ta = 25°C)

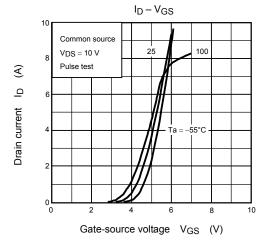
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Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I _{GSS}	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА
Drain cutoff curre	ent	I _{DSS}	V _{DS} = 250 V, V _{GS} = 0 V	_	_	100	μА
		V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	250	_	_	
Drain-source bre	akdown voltage	,,	$I_D = 10 \text{ mA}, V_{GS} = -5 \text{ V}$	250		_	V
		V (BR) DSX	$I_D = 10 \text{ mA}, V_{GS} = -20 \text{ V}$	200	_	_	
Gate threshold voltage		V _{th}	$V_{DS} = 10 \text{ V}, I_D = 1 \text{ mA}$	2.0	_	4.0	V
Drain-source ON-resistance		R _{DS} (ON)	V _{GS} = 10 V, I _D = 2 A	_	0.47	0.58	Ω
Forward transfer admittance		Y _{fs}	$V_{DS} = 10 \text{ V}, I_D = 2 \text{ A}$	1.5	3.3	_	S
Input capacitance	•	C _{iss}		_	600	_	
Reverse transfer	capacitance	C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	20	_	pF
Output capacitance		Coss		_	220	_	
Switching time	Rise time	t _r	VGS 10 V	_	8	_	ns
	Turn-on time	t _{on}		_	17	_	
	Fall time	t _f		_	13	_	
	Turn-off time	t _{off}	Duty ≦ 1%, t _w = 10 μs	_	70	_	
Total gate charge (gate-source plus gate-drain)		Qg		_	10	_	
Gate-source charge		Q _{gs}	$V_{DD} \simeq 200 \text{ V}, V_{GS} = 10 \text{ V},$ $I_D = 4 \text{ A}$	_	7.6	_	nC
Gate-drain ("Miller") charge		Q _{gd}		_	2.4	_	
Gate switch char	ge	Q _{sw}]	_	3.7	_	

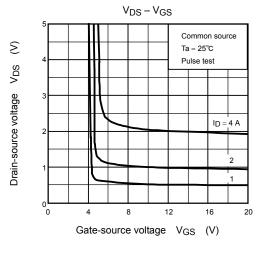
Source-Drain Ratings and Characteristics (Ta = 25°C)

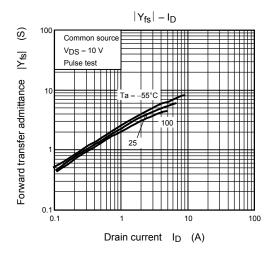
Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit	
Drain reverse current	Pulse	(Note 1)	I _{DRP}	_	_	_	8	Α
Forward voltage (diode)			V_{DSF}	$I_{DR} = 4 A$, $V_{GS} = 0 V$	_	_	-2.0	V

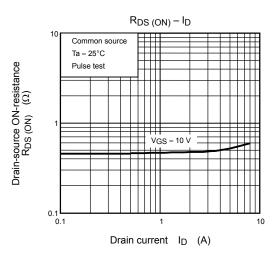




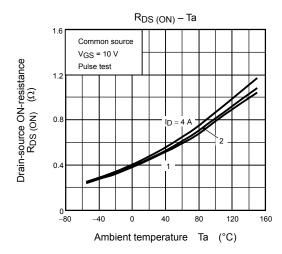


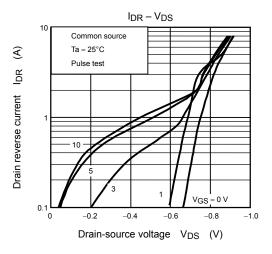


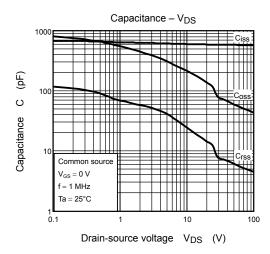


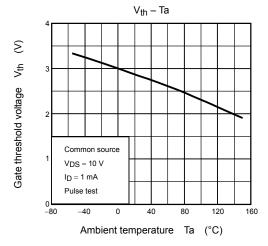


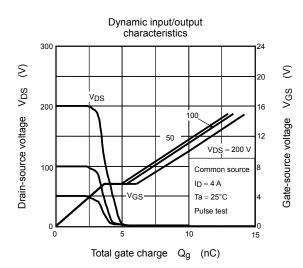
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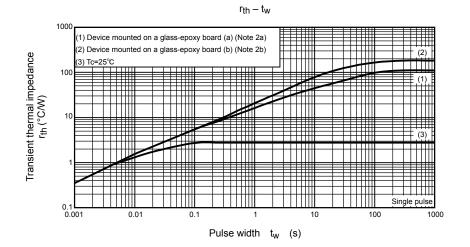


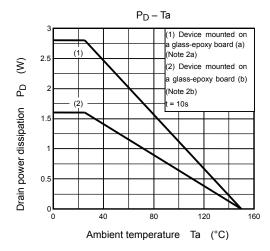


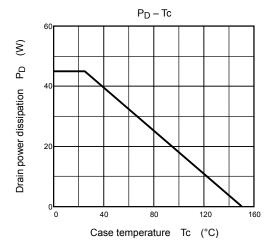


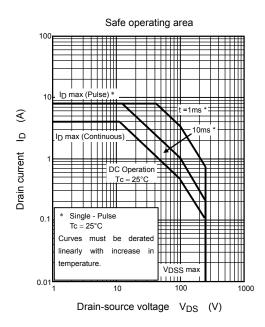


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